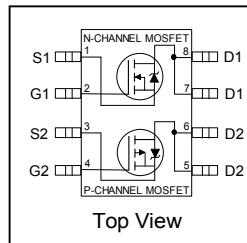


**Features**

- Advanced Planar Technology
- Low On-Resistance
- Logic Level Gate Drive
- Dual N and P Channel MOSFET
- Dynamic dv/dt Rating
- 150°C Operating Temperature
- Fast Switching
- Full Avalanche Rated
- Repetitive Avalanche Allowed up to T<sub>jmax</sub>
- Lead-Free, RoHS Compliant
- Automotive Qualified \*



	N-CH	P-CH
V <sub>DSS</sub>	30V	-30V
R <sub>DS(on)</sub> max.	0.10Ω	0.25Ω
I <sub>D</sub>	3.5A	-2.3A



G	D	S
Gate	Drain	Source

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
AUIRF952Q	SO-8	Tape and Reel	4000	AUIRF952QTR

**Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.		Units
		N-Channel	P-Channel	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	10 Sec. Pulsed Drain Current, V <sub>GS</sub> @ 10V	3.5	-2.3	A
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	2.8	-1.8	
I <sub>DM</sub>	Pulsed Drain Current ①	16	-10	
P <sub>D</sub> @ T <sub>A</sub> = 25°C	Maximum Power Dissipation	2.0		W
P <sub>D</sub> @ T <sub>A</sub> = 70°C	Maximum Power Dissipation	1.3		
	Linear Derating Factor	0.016		
V <sub>GS</sub>	Gate-to-Source Voltage	± 20		V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ③	44	57	mJ
I <sub>AR</sub>	Avalanche Current ①	2.0	-1.3	A
E <sub>AR</sub>	Repetitive Avalanche Energy ①	0.25		mJ
dv/dt	Peak Diode Recovery dv/dt ②	5.0	-5.0	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 150		°C
T <sub>STG</sub>	Storage Temperature Range			

**Thermal Resistance**

Symbol	Parameter	Typ.	Max.	Units
R <sub>θJA</sub>	Junction-to-Ambient ( PCB Mount, steady state) ⑤	—	62.5	°C/W

HEXFET® is a registered trademark of Infineon.

\*Qualification standards can be found at [www.infineon.com](http://www.infineon.com)

**Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

	Parameter		Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	N-Ch	30	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
		P-Ch	-30	—	—		$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	N-Ch	—	0.015	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
		P-Ch	—	-0.015	—		Reference to $25^\circ\text{C}, I_D = -1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	N-Ch	—	0.08	0.10	$\Omega$	$V_{GS} = 10\text{V}, I_D = 2.2\text{A}$ ④
		—	—	0.12	0.15		$V_{GS} = 4.5\text{V}, I_D = 1.0\text{A}$ ④
		P-Ch	—	0.165	0.250		$V_{GS} = -10\text{V}, I_D = -1.0\text{A}$ ④
		—	—	0.290	0.400		$V_{GS} = -4.5\text{V}, I_D = -0.5\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	N-Ch	1.0	—	3.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
		P-Ch	-1.0	—	-3.0		$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$
$g_{fs}$	Forward Trans conductance	N-Ch	—	12	—	S	$V_{DS} = 15\text{V}, I_D = 3.5\text{A}$
		P-Ch	—	2.4	—		$V_{DS} = -15\text{V}, I_D = -2.3\text{A}$
$I_{DSS}$	Drain-to-Source Leakage Current	N-Ch	—	—	2.0	$\mu\text{A}$	$V_{DS} = 24\text{V}, V_{GS} = 0\text{V}$
		P-Ch	—	—	-2.0		$V_{DS} = -24\text{V}, V_{GS} = 0\text{V}$
		N-Ch	—	—	25		$V_{DS} = 24\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
		P-Ch	—	—	-25		$V_{DS} = -24\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	N-P	—	—	$\pm 100$	nA	$V_{GS} = \pm 20\text{V}$
	Gate-to-Source Reverse Leakage	N-P	—	—	$\pm 100$		$V_{GS} = \pm 20\text{V}$

**Dynamic Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

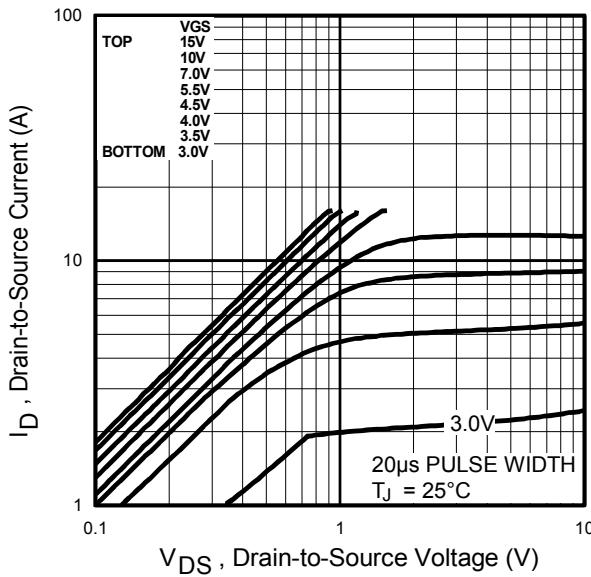
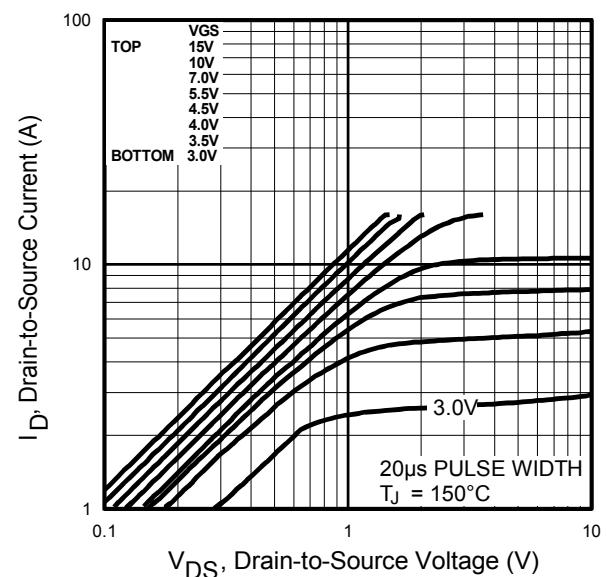
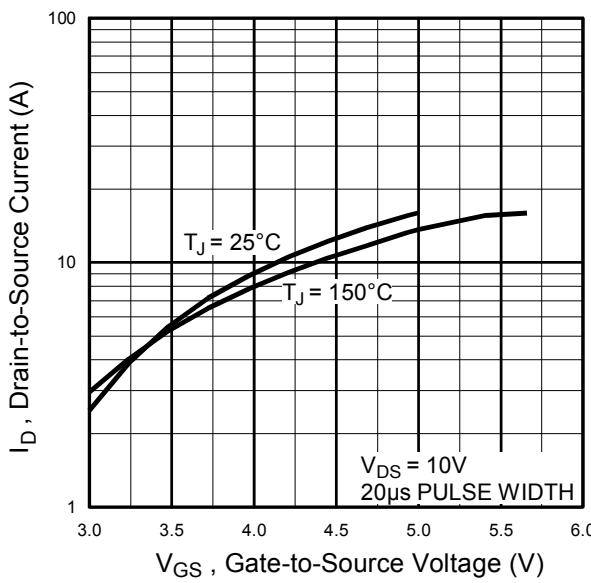
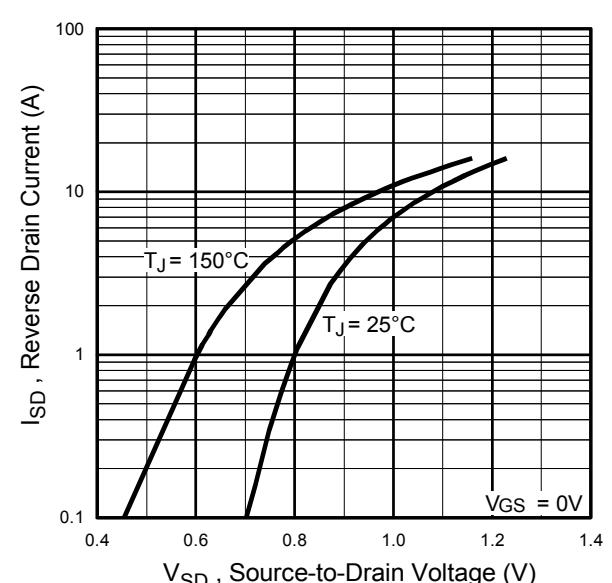
$Q_g$	Total Gate Charge	N-Ch	—	6.9	14	nC	N-Channel $I_D = 1.8\text{A}, V_{DS} = 10\text{V}, V_{GS} = 10\text{V}$ ④
		P-Ch	—	6.1	12		P-Channel $I_D = -2.3\text{A}, V_{DS} = -10\text{V}, V_{GS} = -10\text{V}$
$Q_{gs}$	Gate-to-Source Charge	N-Ch	—	1.0	2.0		
		P-Ch	—	1.7	3.4		
$Q_{gd}$	Gate-to-Drain Charge	N-Ch	—	1.8	3.5	ns	
		P-Ch	—	1.1	2.2		
$t_{d(on)}$	Turn-On Delay Time	N-Ch	—	6.2	12		N-Channel $V_{DD} = 10\text{V}, I_D = 1.0\text{A}, R_G = 6.0\Omega, R_D = 10\Omega$ ④
		P-Ch	—	9.7	19		
$t_r$	Rise Time	N-Ch	—	8.8	18		
		P-Ch	—	14	28		
$t_{d(off)}$	Turn-Off Delay Time	N-Ch	—	13	26	pF	P-Channel $V_{DD} = -10\text{V}, I_D = -1.0\text{A}, R_G = 6.0\Omega, R_D = 10\Omega$
		P-Ch	—	20	40		
$t_f$	Fall Time	N-Ch	—	3.0	6.0		
		P-Ch	—	6.9	14		
$C_{iss}$	Input Capacitance	N-Ch	—	190	—	pF	N-Channel $V_{GS} = 0\text{V}, V_{DS} = 15\text{V}, f = 1.0\text{MHz}$
		P-Ch	—	190	—		
$C_{oss}$	Output Capacitance	N-Ch	—	120	—		P-Channel $V_{GS} = 0\text{V}, V_{DS} = -15\text{V}, f = 1.0\text{MHz}$
		P-Ch	—	110	—		
$C_{rss}$	Reverse Transfer Capacitance	N-Ch	—	61	—		
		P-Ch	—	54	—		

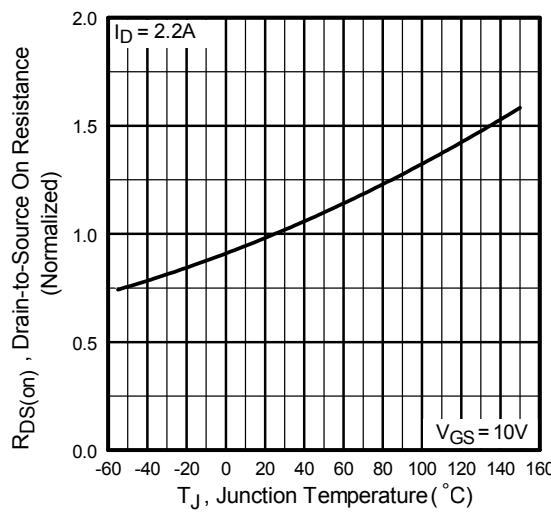
**Diode Characteristics**

	Parameter		Min.	Typ.	Max.	Units	Conditions
$I_s$	Continuous Source Current (Body Diode)	N-Ch	—	—	1.7	A	
		P-Ch	—	—	-1.3		
$I_{SM}$	Pulsed Source Current (Body Diode) ①	N-Ch	—	—	16	ns	
		P-Ch	—	—	-16		
$V_{SD}$	Diode Forward Voltage	N-Ch	—	0.82	1.2	V	$T_J = 25^\circ\text{C}, I_S = 1.25\text{A}, V_{GS} = 0\text{V}$ ④
		P-Ch	—	-0.82	-1.2		$T_J = 25^\circ\text{C}, I_S = -1.25\text{A}, V_{GS} = 0\text{V}$ ④
$t_{rr}$	Reverse Recovery Time	N-Ch	—	27	53	nC	N-Channel $T_J = 25^\circ\text{C}, I_F = 1.25\text{A}, di/dt = 100\text{A}/\mu\text{s}$
		P-Ch	—	27	54		P-Channel $T_J = 25^\circ\text{C}, I_F = -1.25\text{A}, di/dt = 100\text{A}/\mu\text{s}$ ④
$Q_{rr}$	Reverse Recovery Charge	N-Ch	—	28	57	nC	
		P-Ch	—	31	62		
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)					

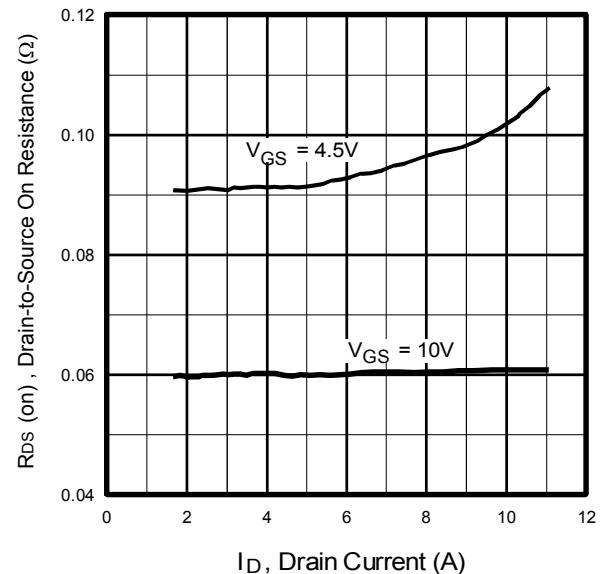
**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig.23)
- ② N-Channel  $I_{SD} \leq 2.0\text{A}$ ,  $di/dt \leq 100\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(\text{BR})\text{DSS}}$ ,  $T_J \leq 150^\circ\text{C}$ .  
P-Channel  $I_{SD} \leq -1.3\text{A}$ ,  $di/dt \leq 84\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(\text{BR})\text{DSS}}$ ,  $T_J \leq 150^\circ\text{C}$ .
- ③ N-Channel Starting  $T_J = 25^\circ\text{C}$ ,  $L = 22\text{mH}$   $R_G = 25\Omega$ ,  $I_{AS} = 2.0\text{A}$ .(See Figure 12)  
P-Channel Starting  $T_J = 25^\circ\text{C}$ ,  $L = 67\text{mH}$   $R_G = 25\Omega$ ,  $I_{AS} = -1.3\text{A}$ .
- ④ Pulse width  $\leq 300\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ⑤ Surface mounted on FR-4 board ,  $t \leq 10\text{sec}$ .

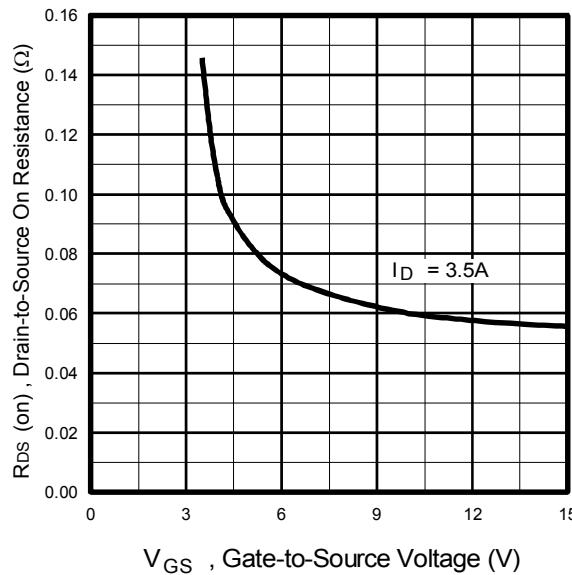
**Fig. 1** Typical Output Characteristics**Fig. 2** Typical Output Characteristics**Fig. 3** Typical Transfer Characteristics**Fig. 4** Typical Source-Drain Diode Forward Voltage



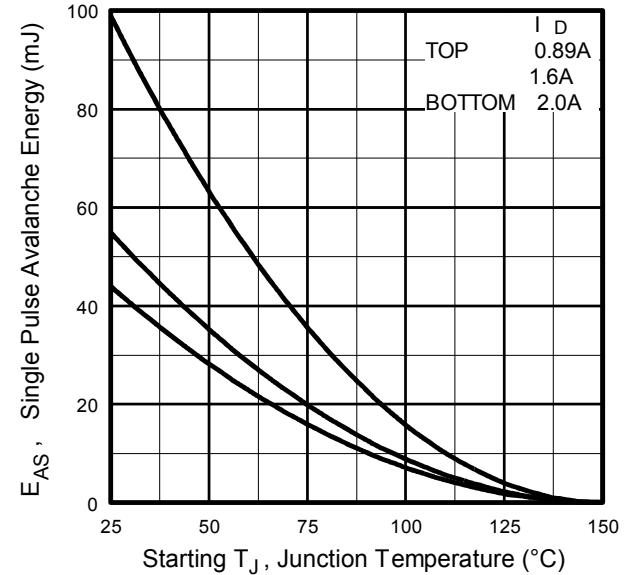
**Fig 5.** Normalized On-Resistance Vs. Temperature



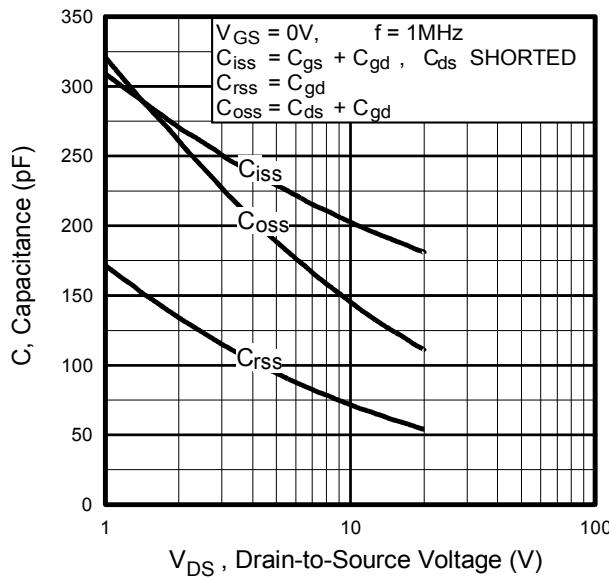
**Fig 6.** Typical On-Resistance Vs. Drain Current



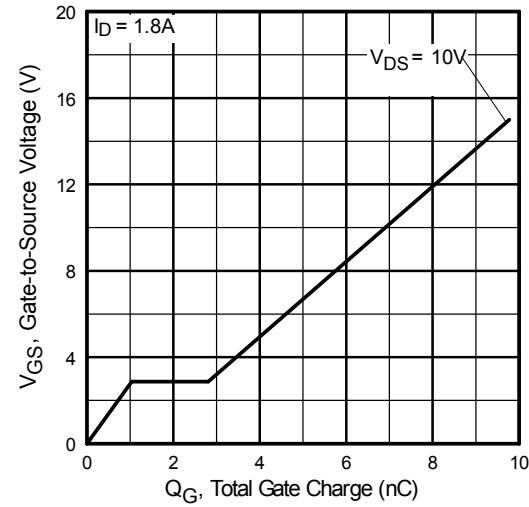
**Fig. 7** Typical On-Resistance Vs. Gate Voltage



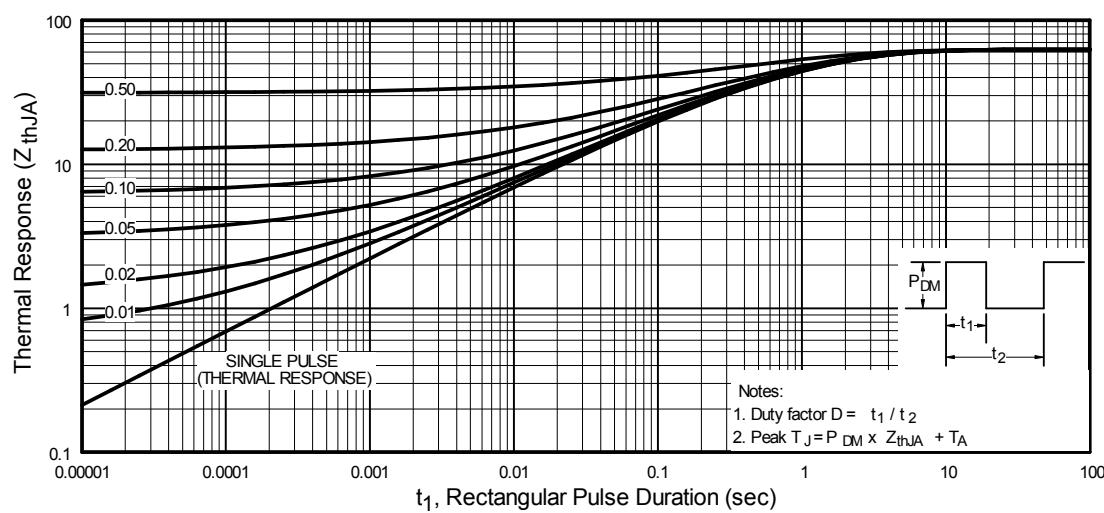
**Fig 8.** Maximum Avalanche Energy Vs. Drain Current



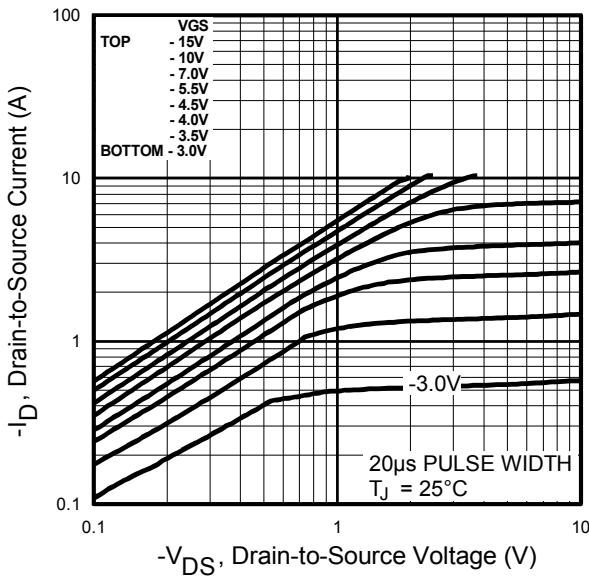
**Fig 9.** Typical Capacitance Vs.  
Drain-to-Source Voltage



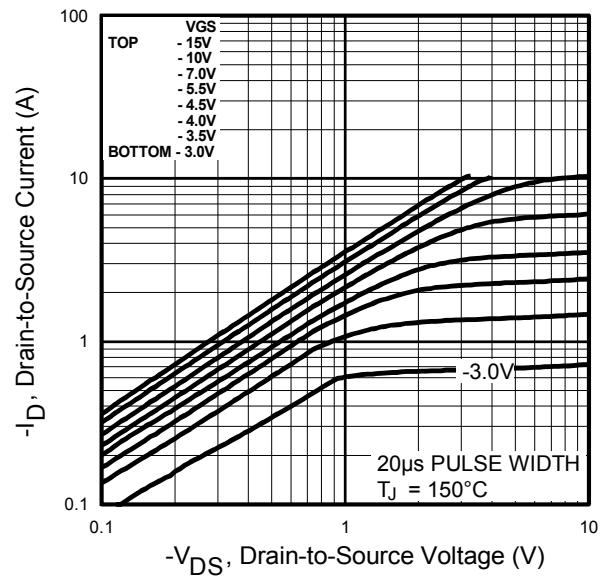
**Fig 10.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



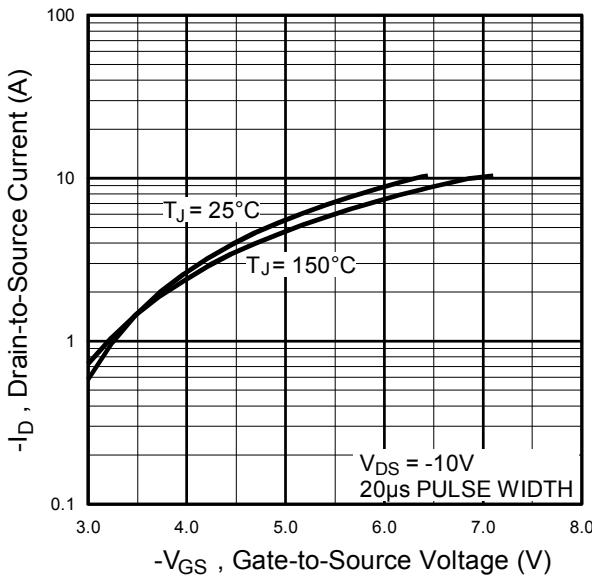
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient



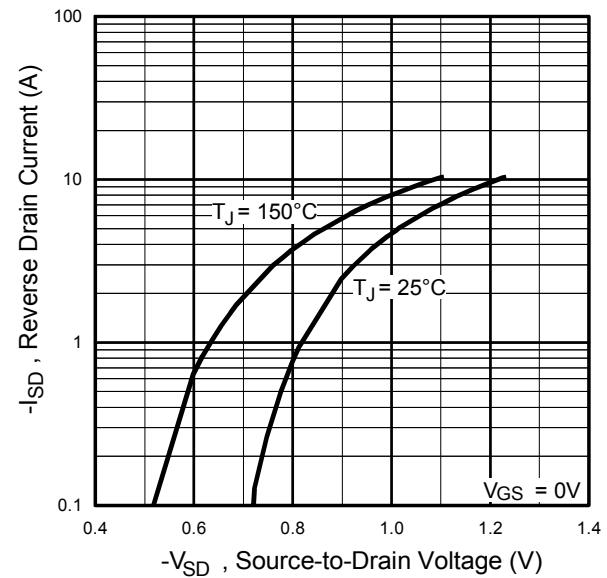
**Fig. 12** Typical Output Characteristics



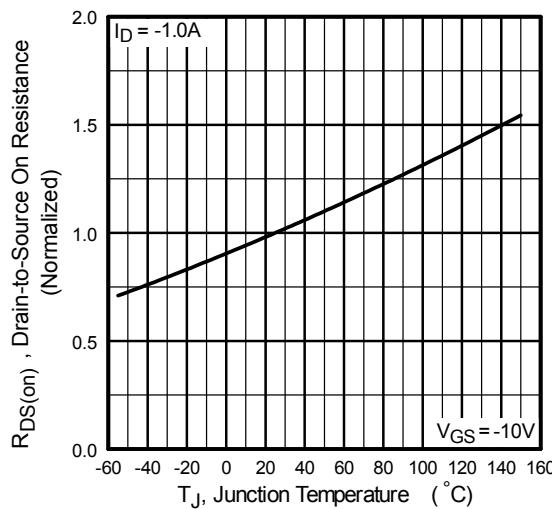
**Fig. 13** Typical Output Characteristics



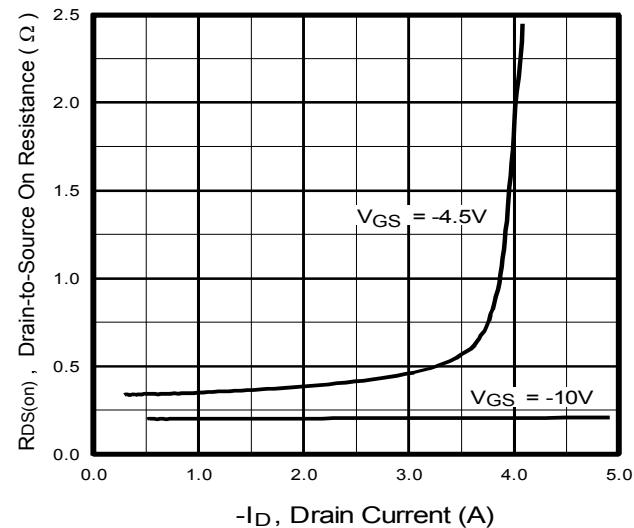
**Fig. 14** Typical Transfer Characteristics



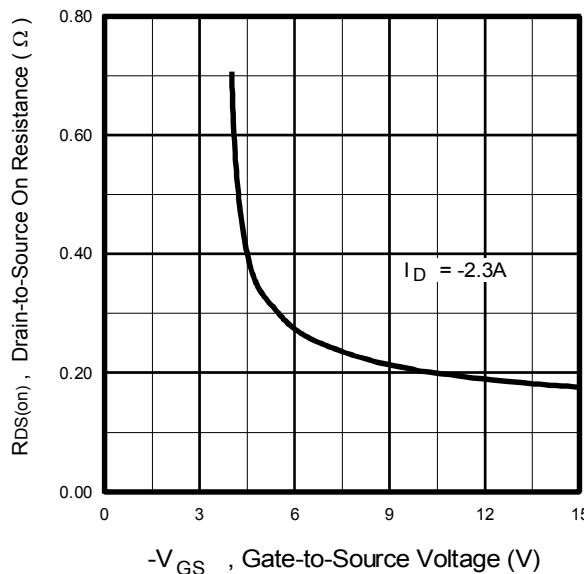
**Fig. 15** Typical Source-Drain Diode Forward Voltage



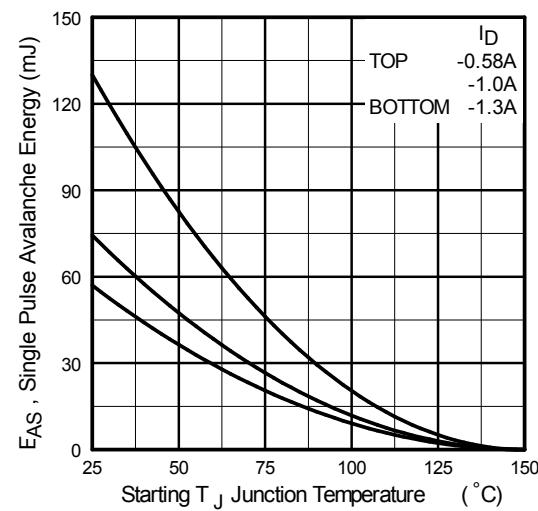
**Fig 16.** Normalized On-Resistance Vs. Temperature



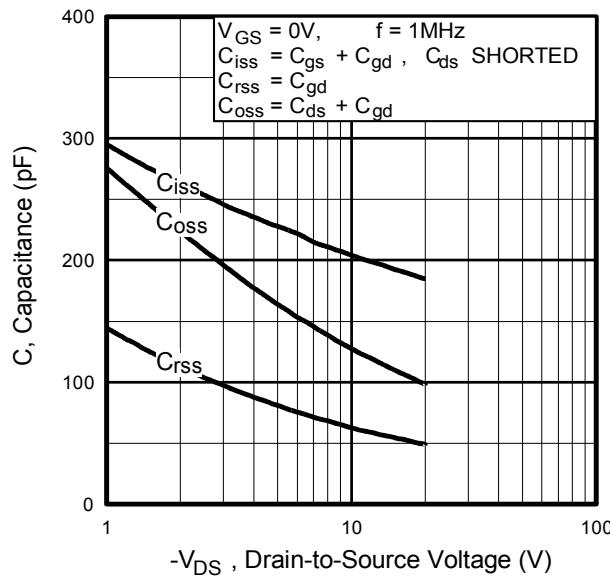
**Fig 17.** Typical On-Resistance Vs. Drain Current



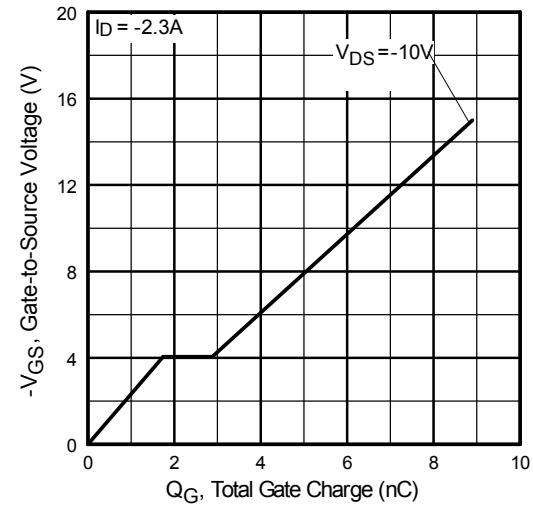
**Fig 18** Typical On-Resistance Vs. Gate Voltage



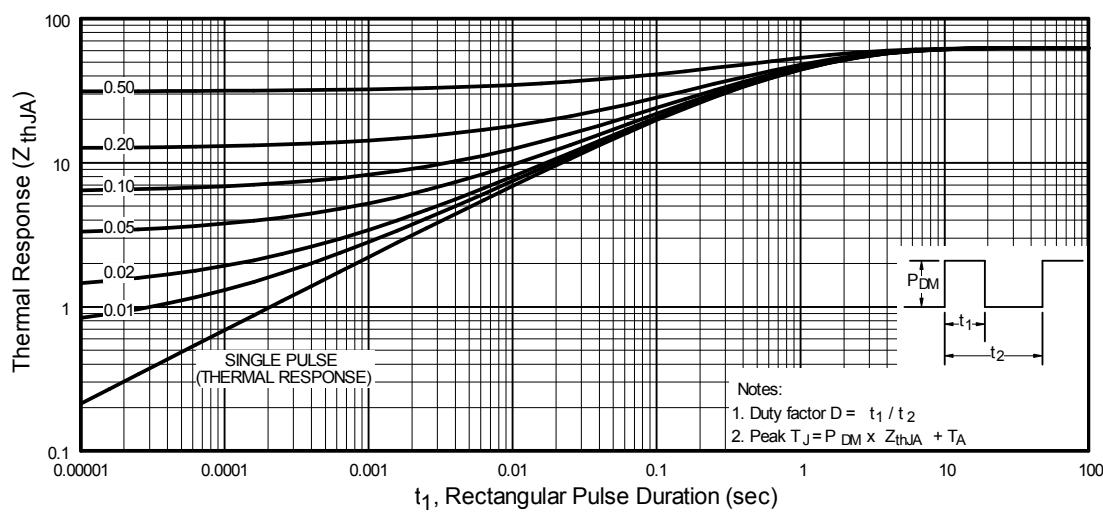
**Fig 19.** Maximum Avalanche Energy Vs. Drain Current



**Fig 20.** Typical Capacitance Vs.  
Drain-to-Source Voltage

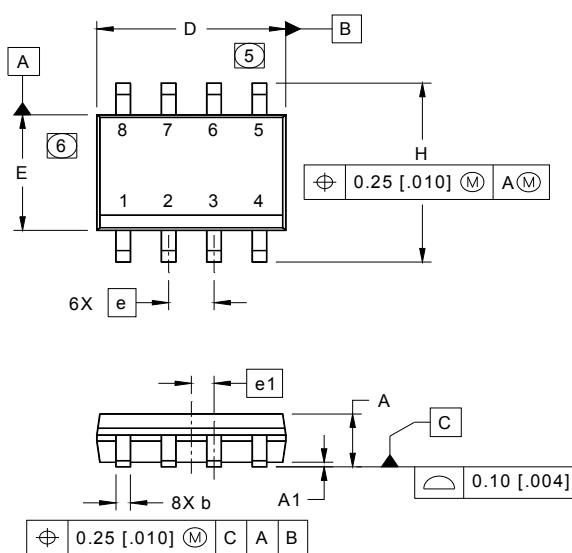


**Fig 21.** Typical Gate Charge Vs.  
Gate-to-Source Voltage

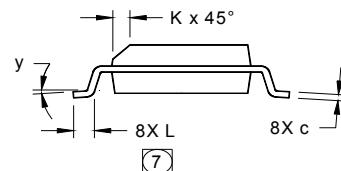


**Fig 22.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

## SO-8 Package Outline (Dimensions are shown in millimeters (inches))

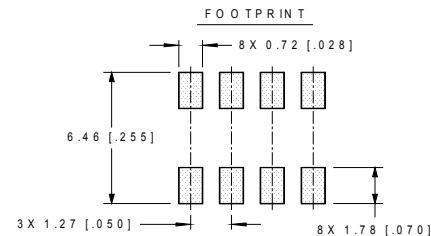


DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050	BASIC	1.27	BASIC
e 1	.025	BASIC	0.635	BASIC
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°

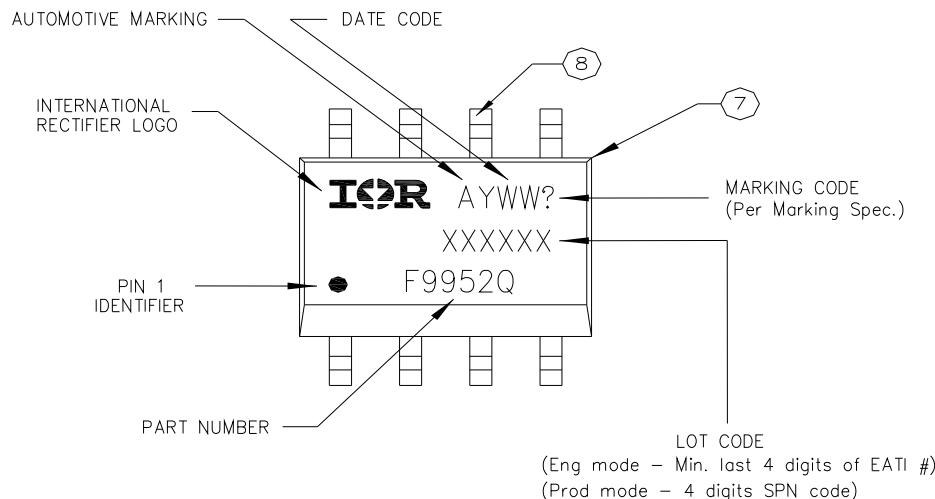


NOTES:

1. DIMENSIONING & TOLERANCING PER ASME Y14.5M -1994.
2. CONTROLLING DIMENSION: MILLIMETER
3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
5. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS.  
MOLD PROTRUSIONS NOT TO EXCEED 0.15 [0.06].
6. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS.  
MOLD PROTRUSIONS NOT TO EXCEED 0.25 [0.10].
7. DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO  
A SUBSTRATE.

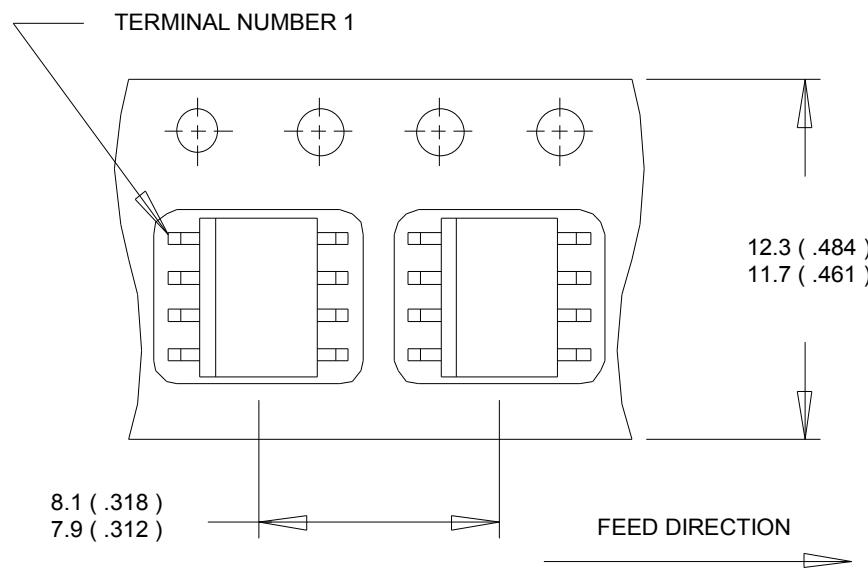


## SO-8 Part Marking Information



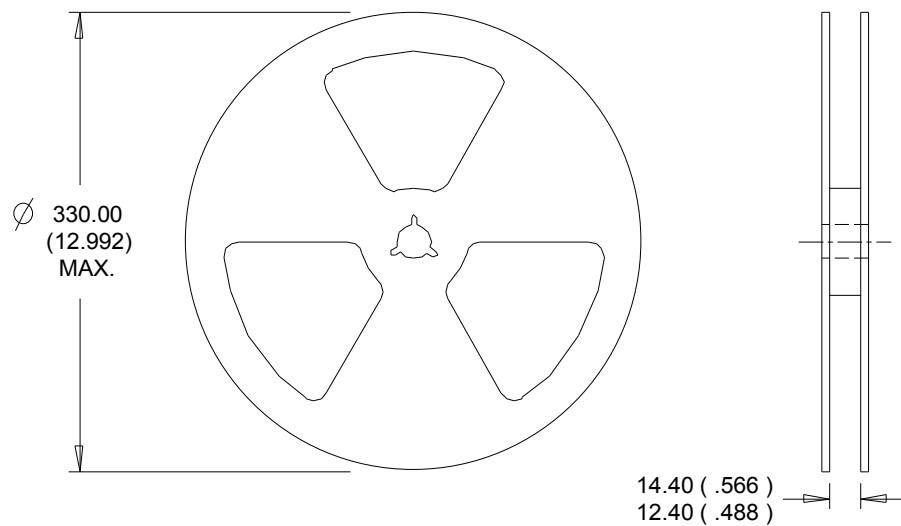
Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**SO-8 Tape and Reel** (Dimensions are shown in millimeters (inches))



NOTES:

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**Qualification Information**

<b>Qualification Level</b>		Automotive (per AEC-Q101)	
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
<b>Moisture Sensitivity Level</b>	SO-8	MSL1	
<b>ESD</b>	Machine Model	N Ch: Class M1A (+/- 50V) <sup>†</sup> P Ch: Class M1A (+/- 50V) <sup>†</sup> AEC-Q101-002	
	Human Body Model	N Ch: Class H0 (+/- 150V) <sup>†</sup> P Ch: Class H0 (+/- 150V) <sup>†</sup> AEC-Q101-001	
	Charged Device Model	N Ch: Class C4 (+/- 1000V) <sup>†</sup> P Ch: Class C4 (+/- 1000V) <sup>†</sup> AEC-Q101-005	
<b>RoHS Compliant</b>	Yes		

<sup>†</sup> Highest passing voltage.

**Revision History**

Date	Comments
3/5/2014	<ul style="list-style-type: none"> <li>• Added "Logic Level Gate Drive" bullet in the features section on page 1</li> <li>• Updated data sheet with new IR corporate template</li> </ul>
10/5/2015	<ul style="list-style-type: none"> <li>• Updated datasheet with corporate template</li> <li>• Corrected ordering table on page 1.</li> </ul>

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